

INSTRUMENTATION (II/II)

Course Code: ENEX - 252
(Module#2)

Dhawa Sang Dong, MSc Eng.
(Sr. Lecturer)

KATHMANDU ENGINEERING COLLEGE
Kalimati, Kathmandu

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CHAPTER #2

THEORY OF MEASUREMENT

✓ Class Outline

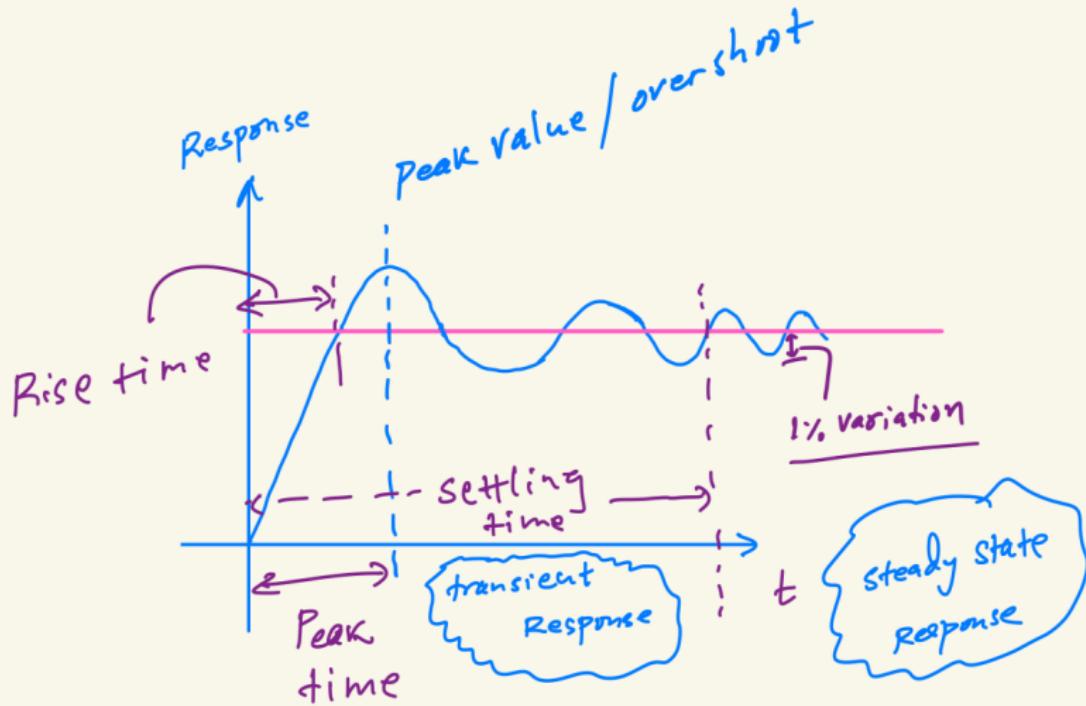
- ① Introduction
- ② Static and Dynamic Performance
- ③ Error in Measurement
- ④ Measurement of Resistance

Introduction

Theory of measurement

- The theory of measurement refers to the scientific principles and methodologies used to obtain quantitative information about physical variables using instruments.
- It is a crucial part of electrical, electronics, and mechanical engineering making measured value less erroneous.
- making error less measurement requires knowledge of characteristics and operations of instrument, basic laws to handle instrument, and cause of error.
- Therefore, study of characteristics of instruments includes
 - ✓ Error and its analysis,
 - ✓ Statistical analysis and
 - ✓ Error minimization

Static and Dynamic Performance



Static and Dynamic Performance

- Immediately after input is applied, the response does not take its expected value.
- Response passes through a period where it changes its value with time – **transient period/response**.
- The behavior during the period is – **Dynamic Characteristics**.
- After transient period, the response takes its value either fluctuation with acceptable variation or constant value – **steady state period**
- The behavior during the period is – **Static Characteristics**.

Statistical Performance Parameters

Static Characteristics

- Statistical parameters are studied during the **steady-state** of a system, not the transient phase.
- The system output is stable, so variations are due to **measurement noise, repeatability, or bias** — ideal for assessing accuracy and precision.
 - ① Accuracy
 - ② Precision or Repeatability
 - ③ Resolution
 - ④ Sensitivity
 - ⑤ Linearity

Statistical Performance Parameters

① Accuracy: | Static Characteristics

- Closeness of a measurement to the true or accepted value.

② Precision or repeatability: | Static Characteristics

- it is measure of consistency, how consistently a measurement system gives the same output for the same input under unchanged conditions.

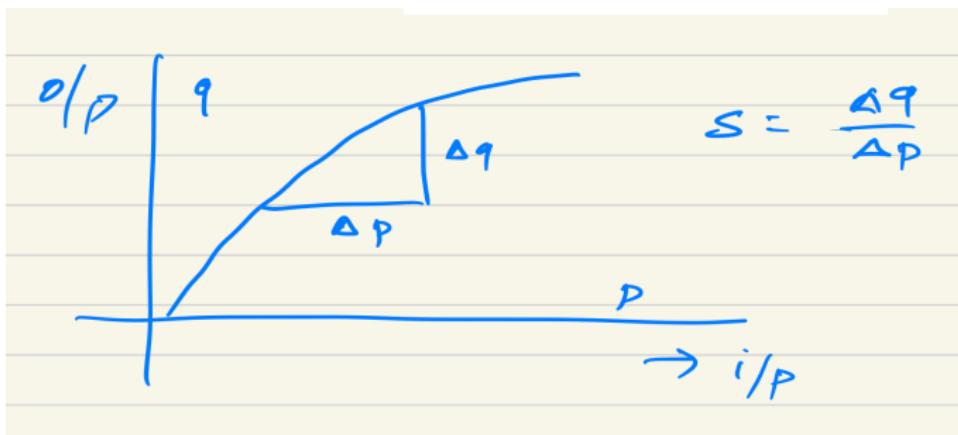
③ Resolution: | Static Characteristics

- maximum change in input for which there is no output changed
- the minimum change in input for which there is detectable changes occur in output.

Statistical Performance Parameters

④ Sensitivity: | Static Characteristics

- ratio of change in output to a change in input; it measures how responsive the system is.
 - when the curve is linear than sensitivity is constant.



Statistical Performance Parameters

⑤ Linearity: | Static Characteristics

- linear system means constant sensitivity; it defines the reproduceable characteristics. $y = mx + c$
- That is, how well the output follows a straight-line relationship with the input across the entire range.

Dynamic Performance Parameters

Dynamic Characteristics

- it describes how the system behaves when the measured quantity (input) changes with time.
 - they are important when the system is subjected to time-varying signals and response is not instantaneous.
- ① Response time,
 - ② Time Constant
 - ③ Frequency Response
 - ④ bandwidth
 - ⑤ Rise time
 - ⑥ Delay time

Dynamic Performance Parameters

① Response Time: | Dynamic Characteristics

- In measurement systems, unless explicitly stated otherwise, response time is typically the total time required to reach the steady state (settling time), not just the time to begin responding.

② Time Constant: | Dynamic Characteristics

- Time it takes for the system's response to reach 63.2% of its final value after a step input

③ Bandwidth: | Dynamic Characteristics

- Frequency range over which the system accurately responds

Dynamic Performance Parameters

④ Frequency Response: | Dynamic Characteristics

- It describes how the system behaves when subjected to sinusoidal inputs of varying frequencies.

Amplitude Ratio (Gain)

- The ratio of the output signal amplitude to the input signal amplitude as a function of frequency.

Phase Shift

- The delay (in degrees or radians) between the input and output signals.

Dynamic Performance Parameters

⑤ Rise Time: | Dynamic Characteristics

- Time taken to rise from 10% to 90% of the final value
- Short rise time means a faster system response to inputs.

⑥ Delay Time: | Dynamic Characteristics

- Time between the application of input and the beginning of the output response
- Delays can lead to instability or lag in feedback systems.

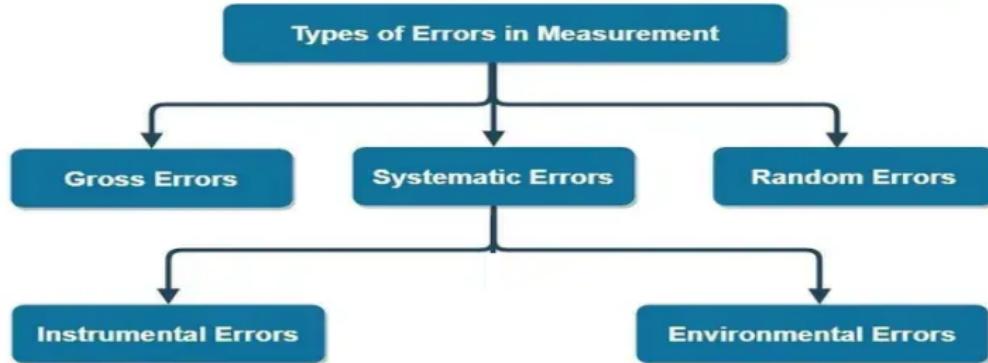
Error in Measurement

Error in Measurement

- it is the deviation of the measured value (M.V) from the true value (T.V) of the quantity under measurement.
 - so error estimate:

$$\text{error} = \frac{\text{true value} - \text{measured value}}{\text{true value}} \times 100\%$$

- Errors may come from different sources and usually classified to be three main types



Error in Measurement

Gross Error: | Error in Measurement

- ✓ is the error due to users:
 - error in calculation,
 - error in observation,
 - error in connections,
 - error in placement

Corrective Methods:

Careful measurement

At least three measurement for the same quantity
by different users.

Error in Measurement

Sytematic Error: | Error in Measurement

① Instrumental Error:

errors are due to
short-coming of instruments,
less accuracy in scale calibration
errors due to defective parts
improper tension in spring.

Corrective Methods:

use of standard instrument
re-calibration or correct scaling
use of correlation factors

Error in Measurement

Sytematic Error: | Error in Measurement

② Environmental Error:

variation in temperature, humidity

error due to external electro-static/magnetic field.

Corrective Methods:

measurement in air-conditioned room

casing for pressure and humidity effect

use of shielding

Error in Measurement

Random Error: | Error in Measurement

- ✓ cause of error is unknown
 - this type of error can't be corrected

Corrective Methods:

- use of statistical analysis – mean (arithmetic)
- use the statistical analysis only after minimizing gross error and systematic error

Error in Measurement

Random Error: | Error in Measurement

✓ Statistical Analysis:

arithmetic mean

deviation

average deviation (\sim zero)

standard deviation / RMS (σ)

variance (v)

Error in Measurement

Summary of Error: | Error in Measurement

Error Type	Crucial When	Why Critical
Gross	Due to human mistakes or negligence	Often large errors; easily preventable
Systematic	When left undetected in long-term measurements or automated systems	Leads to consistently wrong decisions
Random	In ultra-precise systems (e.g., quantum sensors, nanotech)	Affects resolution; can be minimized but not avoided

Errors in Measurement

What is next?

Explore more on:

- ✓ What are the different methods to measure low resistance? see detailed circuit diagram on ammeter-voltmeter method.
- ✓ What is AC/DC bridge? detailed of circuit diagram and mathematics.

- ✓ block diagram and basic relations of arm parameters.
 - ① Wheat-stone bridge,
 - ② maxwell's bridge,
 - ③ Schering's bridge

Measurement of Resistance

Low Resistance Measurement

- there are three types of methods to measure low resistance
 - ① Ammeter - Voltmeter method**
 - ② Kelvin's double bridge method**
 - ③ Potentio-meter method**

Measurement of Resistance

Ammeter-Voltmeter method: | Low Resistance Measurement

- Consider the following circuit diagram:
 - measure of Resistance

$$R_m = \frac{V}{I} \quad \rightarrow \quad R = R_m \left[1 + \frac{R_m}{R_v} \right]$$

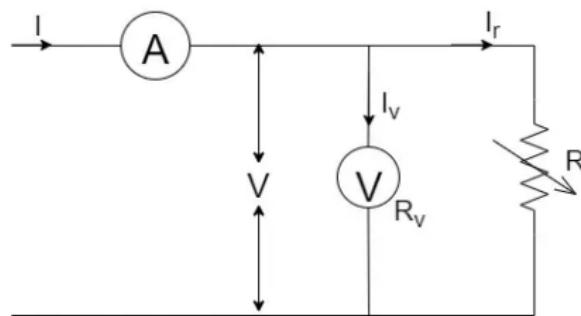


Fig. 1 Measurement of resistance by ammeter-voltmeter method

Measurement of Resistance

Ammeter-Voltmeter method: | Low Resistance Measurement

- Consider the following circuit diagram:

measure of Resistance

$$R_m = \frac{V}{I}$$

$$= \frac{V}{I_r + I_v}$$

$$= \frac{V}{\frac{V}{R} + \frac{V}{R_v}}$$

$$= \frac{R}{1 + \frac{R}{R_v}}$$

True of Resistance

$$R = \frac{V}{I_r}$$

$$= \frac{V}{I - I_v} = \frac{V}{I - \frac{V}{R_v}}$$

$$= \frac{V}{I \left(1 - \frac{V}{R_v \times I}\right)}$$

$$R = \frac{R_m}{1 - \frac{R_m}{R_v}}$$

Measurement of Resistance

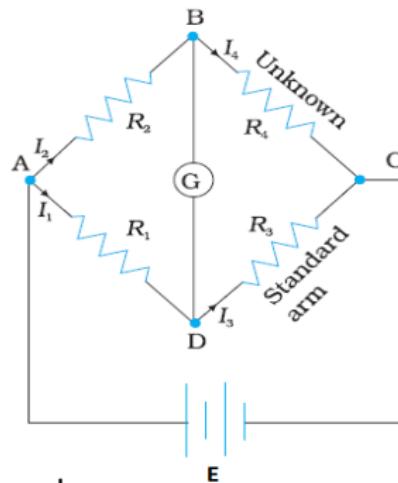
Wheatstone Bridge – DC Bridge

- A very important circuit used to measure medium resistance.

For balanced circuit,

galvanometer current is zero

$$I_1 R_1 = I_2 R_2 \dots \dots \text{(a)}$$



Substituting I_1 and I_2 from b and c to a

$$R_1 R_4 = R_2 R_3 \rightarrow R_4 = \frac{R_2 R_3}{R_4}$$

Measurement of Impedance Components

AC Bridge

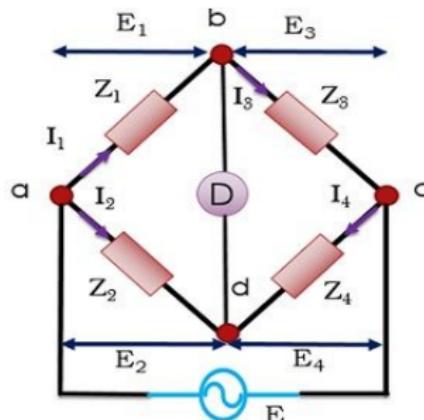
- when excitation voltage or current to the bridge circuit is alternating, the bridge is ac bridge;
 - the ac bridge circuit is used to measure impedance components such as inductance, capacitance, loss factor.

- ✓ For balanced circuit,
current through Detector is zero

$$I_1 Z_1 = I_2 Z_2 \dots \dots \text{(i)}$$

Substituting I_1 and I_2 from (ii) and (iii) to (i)

$$Z_1 Z_4 = Z_2 Z_3$$



Measurement of Impedance Components

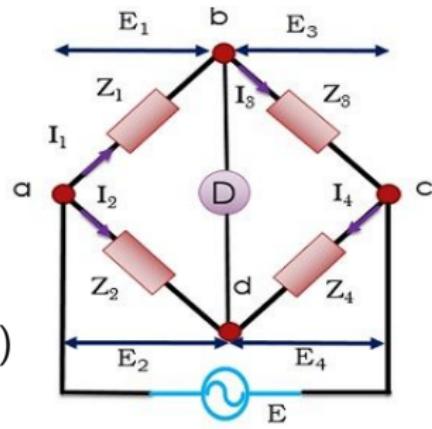
AC Bridge

- ✓ When considered polar form of the impedance;

 - ① the product of magnitude of any two opposite arms impedance must be equal to the product of magnitude of other two arm's impedance.
 - ② the sum of phase angle of any two opposite arm impedance must be equal to that of other two.

- ✓ For balanced circuit,
current through Detector is zero
 $Z_1Z_4 = Z_2Z_3 \dots \dots \text{(iv)}$

$$|Z_1||Z_4|\angle(\theta_1 + \theta_4) = |Z_2||Z_3|\angle(\theta_2 + \theta_3)$$



Measurement of Impedance Components

Maxwell's Bridge – AC Bridge

- Inductance L_x is measured in terms of capacitance known.

From the circuit diagram:

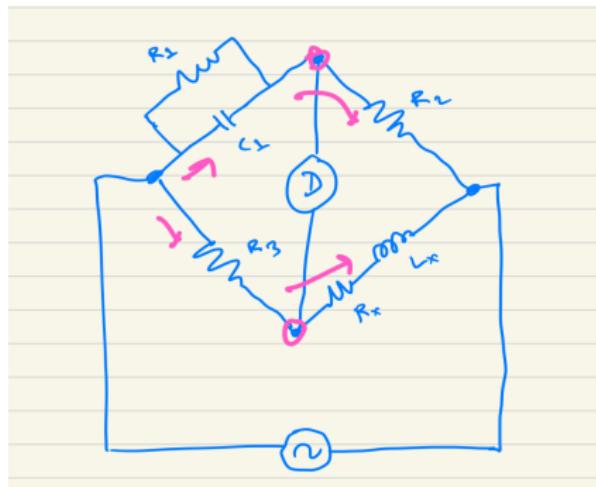
$$Z_2 = R_2 \angle 0$$

$$Z_x = R_x + jX_L$$

$$Z_x = R_x + jwL_x$$

$$Z_3 = R_3 \angle 0$$

$$Y_1 = \frac{1}{R_1} + jwC_1$$



Measurement of Impedance Components

Maxwell's Bridge – AC Bridge

- Inductance L_x is measured in terms of capacitance known.

For balanced AC bridge:

$$Z_1 Z_x = Z_2 Z_3$$

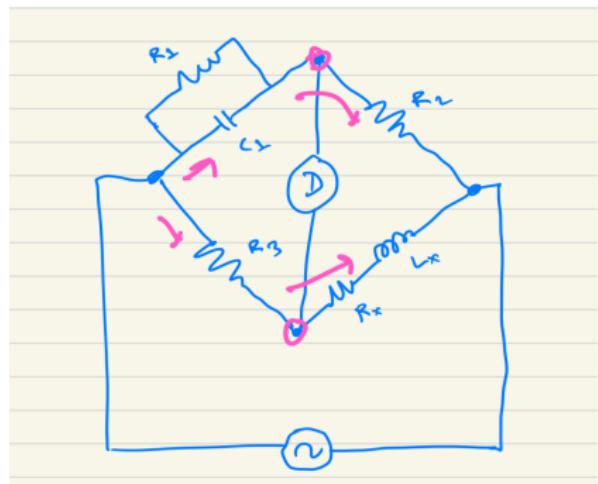
$$Z_x = \frac{z_2 z_3}{Z_1} \quad (Y_1 = \frac{1}{Z_1})$$

$$Z_x = R_2 R_3 \left(\frac{1}{R_1} + j w c_1 \right)$$

$$R_x + jwL_x = R_2 R_3 \left(\frac{1}{R_1} + jwc_1 \right)$$

$$R_x + jwL_x = \frac{R_2}{R_1} R_3 + jwR_2R_3c_1$$

→ Equating real and imaginary parts:



$$R_x = \frac{R_2}{R_1} R_3 \dots \dots (i)$$

$$L_x = R_2 R_3 c_1 \dots \dots (ii)$$

Measurement of Impedance Components

Schering's Bridge – AC Bridge

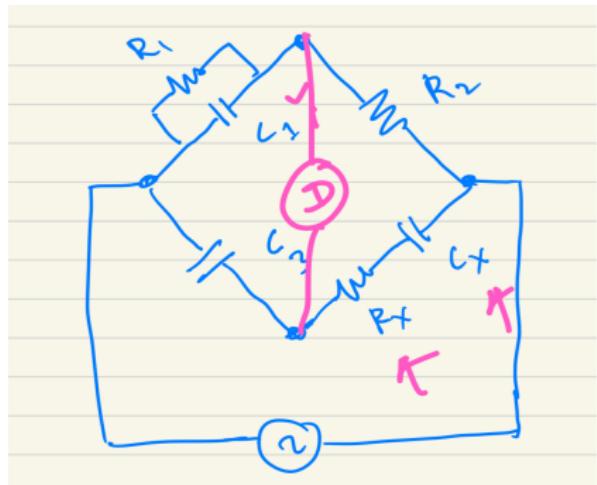
- A very important circuit used to measure Capacitance.

$$Y_1 = \frac{1}{R_1} + j\omega C_1$$

$$Z_2 = R_2$$

$$Z_x = R_x - j \frac{1}{\omega C_x}$$

$$Z_3 = -j \frac{1}{wc_3}$$



Measurement of Impedance Components

Schering's Bridge – AC Bridge

- A very important circuit used to measure Capacitance.

For balanced circuit,

Detector current is zero

$$Z_1 Z_x = Z_2 Z_3$$

$$Z_x = Z_2 Z_3 Y_1$$

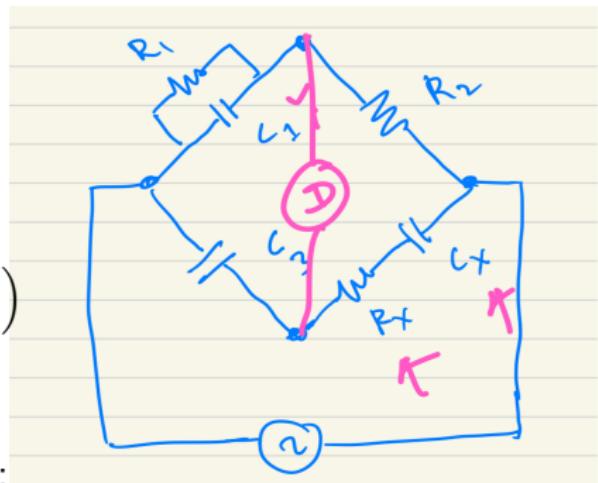
$$R_x - j \frac{1}{w c_x} = R_2 \left(-\frac{j}{w c_3} \right) \left(\frac{1}{R_1} + j w c_1 \right)$$

$$R_x - j \frac{1}{w c_x} = -j \frac{R_2}{w R_1 c_3} + R_2 \frac{c_1}{c_3}$$

→ Equating real and imaginary parts:

$$R_x = \frac{c_1}{c_3} R_2 \dots \dots (i)$$

$$c_x = \frac{R_1}{R_2} c_3 \dots \dots (ii)$$



Maxwell's and Schering's Bridge

Comparative block Diagram

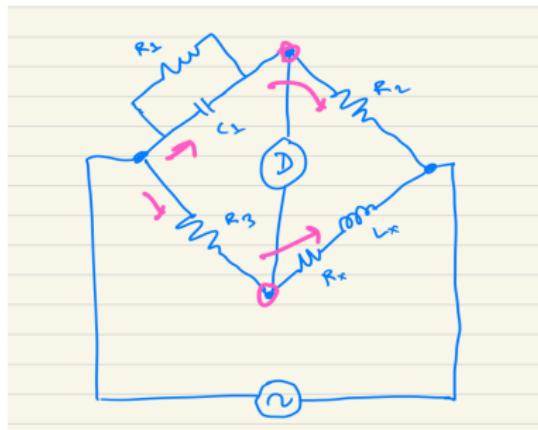


Fig. 2 Maxwell's Bridge

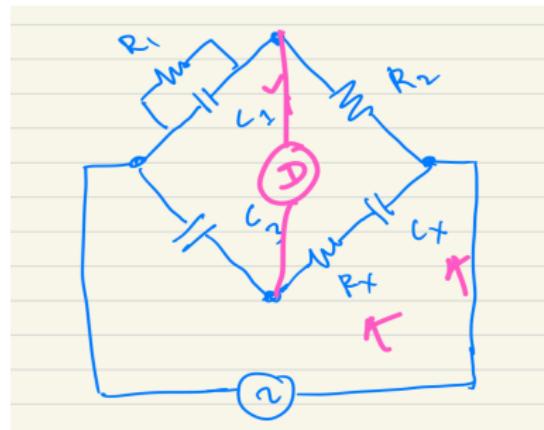


Fig. 3 Schering's Bridge

As you go Assignment

Assignment Module#2 is available at MS-Team.

Submission Deadline: 30th May 2025 (Before 3:00 PM)